

Features

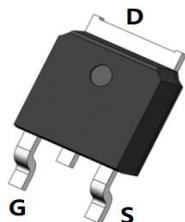
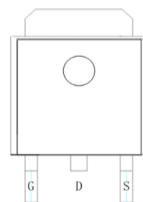
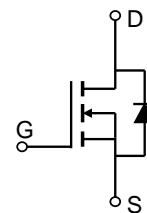
- Excellent $R_{DS(ON)}$ and Low Gate Charge
- 100% UIS Tested
- 100% ΔV_{ds} Tested
- Halogen-free; RoHS-compliant

Applications

- Load Switch
- PWM Application
- Power Management

Product Summary

Parameters	Value	Unit
V_{DSS}	60	V
$V_{GS(th)}_{Typ}$	1.6	V
$I_D(@V_{GS}=10V)$	50	A
$R_{DS(ON)}_{Typ}(@V_{GS}=10V)$	12.2	mΩ
$R_{DS(ON)}_{Typ}(@V_{GS}=4.5V)$	13.7	mΩ


TO-252-3L

Pin Assignment

Schematic Diagram
Ordering Information

Device	Marking	MSL	Form	Package	Reel(pcs)	Per Carton (pcs)
JMTK50N06B	JMTK50N06B	3	Tape&Reel	TO-252-3L	2500	25000

Absolute Maximum Ratings (@ $T_C = 25^\circ\text{C}$ unless otherwise specified)

Symbol	Parameter		Value	Unit
V_{DS}	Drain-to-Source Voltage		60	V
V_{GS}	Gate-to-Source Voltage		± 20	V
I_D	Continuous Drain Current	$T_C = 25^\circ\text{C}$	50	A
		$T_C = 100^\circ\text{C}$	31	
I_{DM}	Pulsed Drain Current ⁽¹⁾		Refer to Fig.4	A
E_{AS}	Single Pulsed Avalanche Energy ⁽²⁾		59	mJ
P_D	Power Dissipation	$T_C = 25^\circ\text{C}$	40.3	W
		$T_C = 100^\circ\text{C}$	16.1	
T_J, T_{STG}	Junction & Storage Temperature Range		-55 to 150	°C

Thermal Characteristics

Symbol	Parameter	Max	Unit
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient ⁽³⁾	49	°C/W
$R_{\theta JC}$	Thermal Resistance, Junction to Case	3.1	

Electrical Characteristics ($T_J = 25^\circ\text{C}$ unless otherwise specified)

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
Off Characteristics						
$V_{(\text{BR})\text{DSS}}$	Drain-Source Breakdown Voltage	$I_D = 250\mu\text{A}, V_{GS} = 0\text{V}$	60	-	-	V
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = 60\text{V}, V_{GS} = 0\text{V}$	-	-	1.0	μA
I_{GSS}	Gate-Body Leakage Current	$V_{DS} = 0\text{V}, V_{GS} = \pm 20\text{V}$	-	-	± 100	nA
On Characteristics						
$V_{GS(\text{th})}$	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_D = 250\mu\text{A}$	1.1	1.6	2.5	V
$R_{\text{DS(ON)}}$	Static Drain-Source ON-Resistance ⁽⁴⁾	$V_{GS} = 10\text{V}, I_D = 30\text{A}$	-	12	15.0	$\text{m}\Omega$
		$V_{GS} = 4.5\text{V}, I_D = 20\text{A}$	-	14	21.0	$\text{m}\Omega$
Dynamic Characteristics						
R_g	Gate Resistance	$f = 1\text{MHz}$	-	2.4	-	Ω
C_{iss}	Input Capacitance	$V_{GS} = 0\text{V}, V_{DS} = 30\text{V}, f = 1\text{MHz}$	1900	2660	3591	pF
C_{oss}	Output Capacitance		85	119	161	pF
C_{rss}	Reverse Transfer Capacitance		69	96	130	pF
Q_g	Total Gate Charge	$V_{GS} = 0 \text{ to } 10\text{V}$ $V_{DS} = 30\text{V}, I_D = 30\text{A}$	36	50	68	nC
Q_{gs}	Gate Source Charge		7	10	14	nC
Q_{gd}	Gate Drain("Miller") Charge		7	9	12	nC
Switching Characteristics						
$t_{d(on)}$	Turn-On DelayTime	$V_{GS} = 10\text{V}, V_{DD} = 30\text{V}$ $I_D = 30\text{A}, R_{\text{GEN}} = 3\Omega$	-	9	-	ns
t_r	Turn-On Rise Time		-	31	-	ns
$t_{d(off)}$	Turn-Off DelayTime		-	44	-	ns
t_f	Turn-Off Fall Time		-	8	-	ns
Body Diode Characteristics						
I_S	Maximum Continuous Body Diode Forward Current	-	-	50	A	
I_{SM}	Maximum Pulsed Body Diode Forward Current	-	-	198	A	
V_{SD}	Body Diode Forward Voltage	$V_{GS} = 0\text{V}, I_S = 30\text{A}$	-		1.2	V
trr	Body Diode Reverse Recovery Time	$I_F = 30\text{A}, di/dt = 100\text{A/us}$	16	22	30	ns
Qrr	Body Diode Reverse Recovery Charge		-	25.2	-	nC

Notes:

1. Repetitive Rating: Pulse Width Limited by Maximum Junction Temperature.

2. E_{AS} condition: Starting $T_J=25^\circ\text{C}$, $V_{DD}=30\text{V}$, $V_{GS}=10\text{V}$, $R_G=25\text{ohm}$, $L=0.5\text{mH}$, $I_{AS}=15.96\text{A}$, $V_{DD}=0\text{V}$ during time in avalanche.

3. $R_{\theta JA}$ is measured with the device mounted on a 1inch² pad of 2oz copper FR4 PCB.

4. Pulse Test: Pulse Width $\leq 300\mu\text{s}$, Duty Cycle $\leq 0.5\%$.



Typical Performance Characteristics

Figure 1: Power De-rating

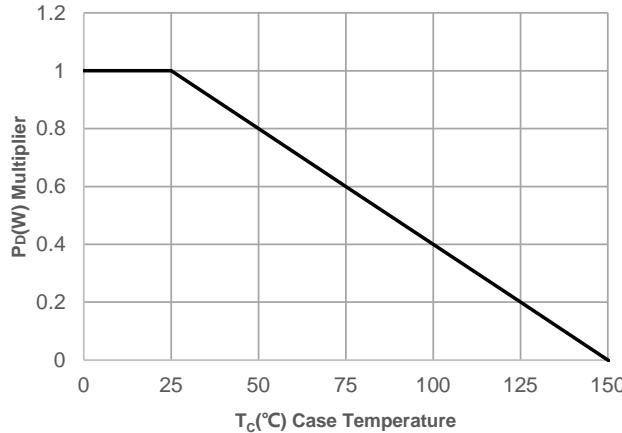


Figure 2: Current De-rating

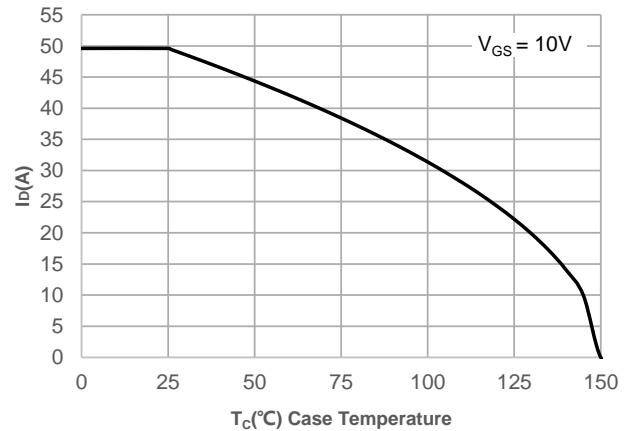


Figure 3: Normalized Maximum Transient Thermal Impedance

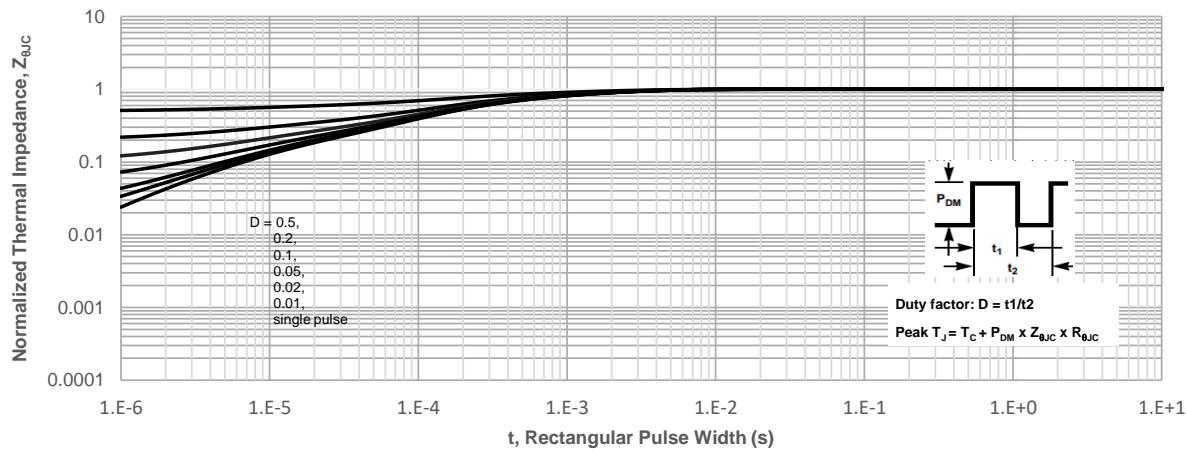
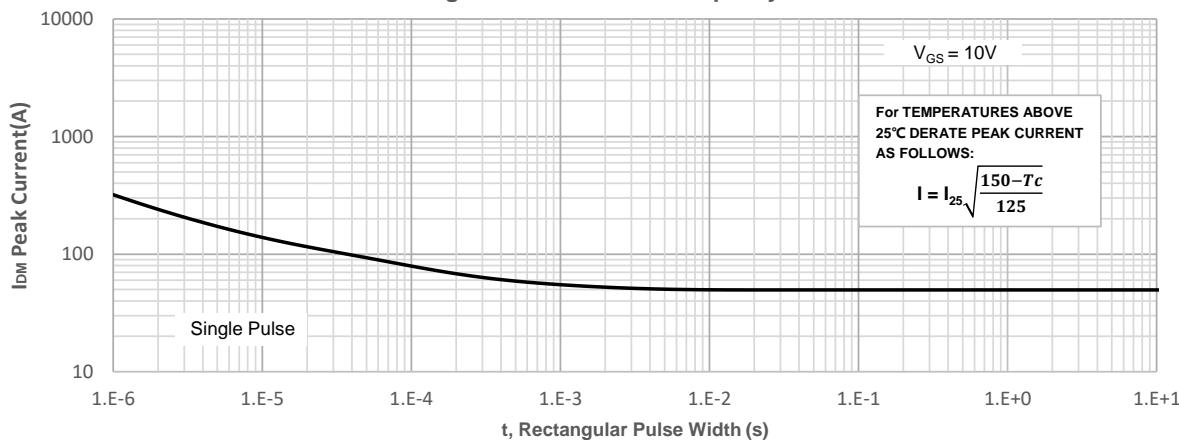


Figure 4: Peak Current Capacity



Typical Performance Characteristics

Figure 5: Output Characteristics

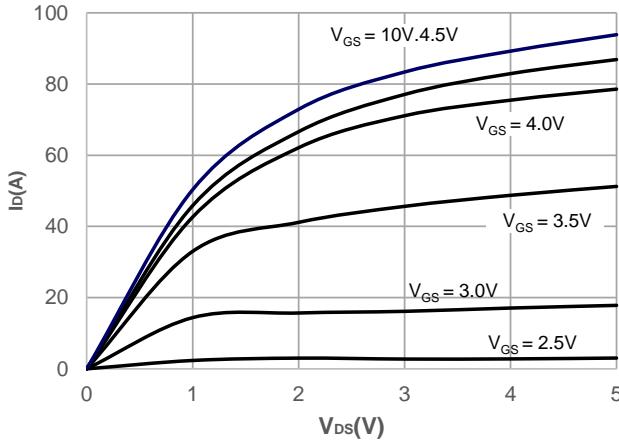


Figure 6: Typical Transfer Characteristics

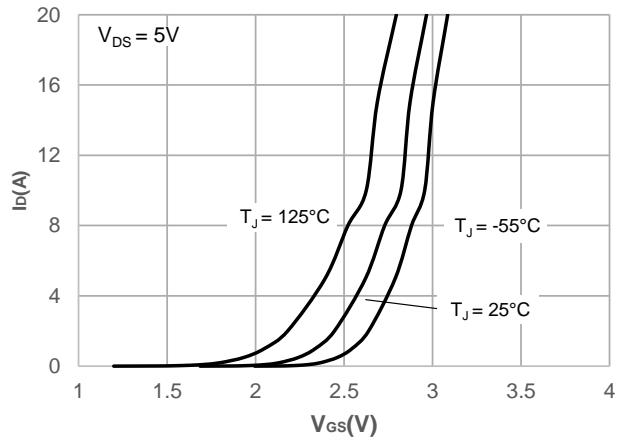


Figure 7: On-resistance vs. Drain Current

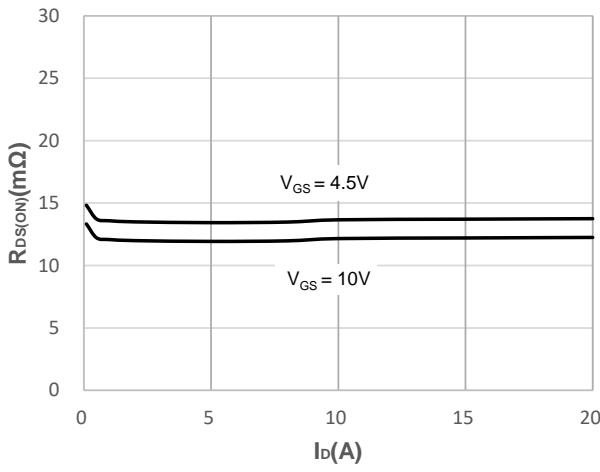


Figure 8: Body Diode Characteristics

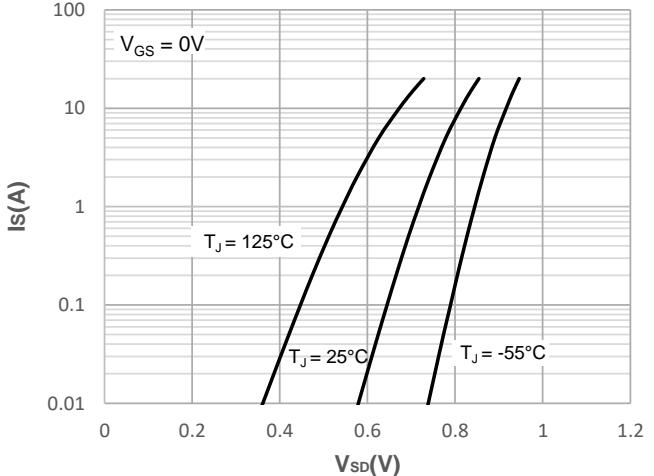


Figure 9: Gate Charge Characteristics

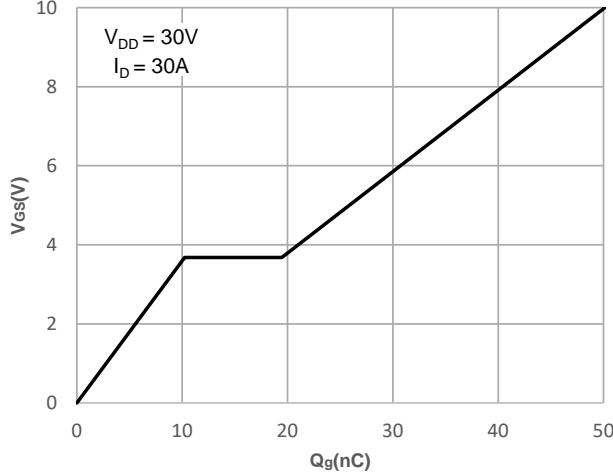
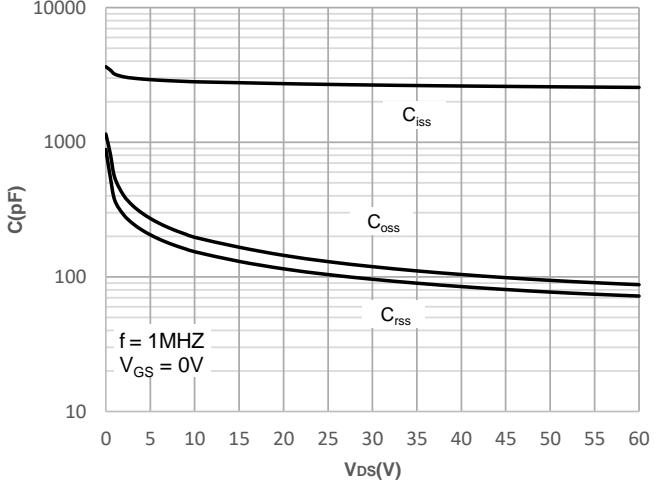


Figure 10: Capacitance Characteristics



Typical Performance Characteristics

Figure 11: Normalized Breakdown voltage vs. Junction Temperature

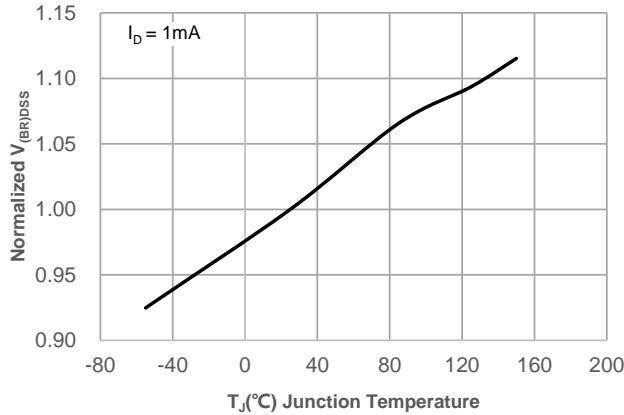


Figure 12: Normalized on Resistance vs. Junction Temperature

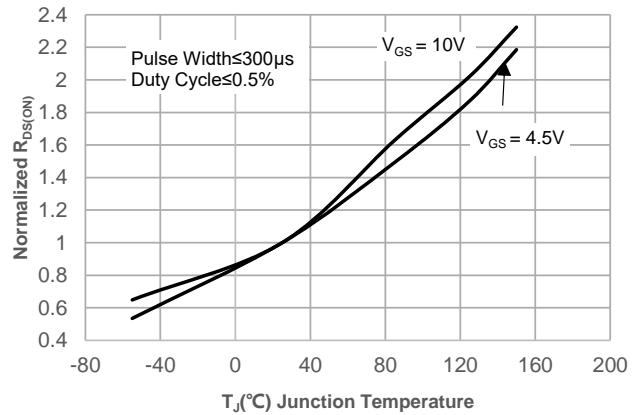


Figure 13: Normalized Threshold Voltage vs. Junction Temperature

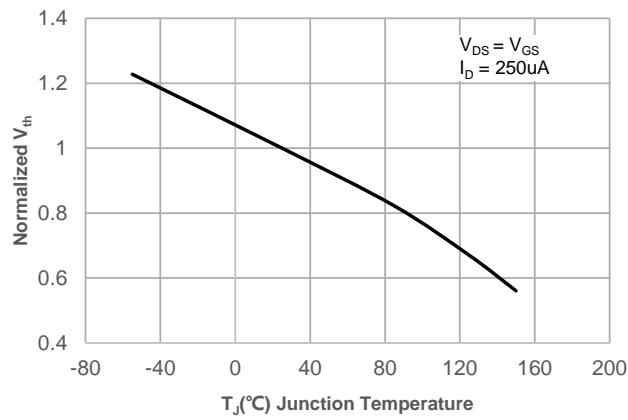


Figure 14: $R_{DS(on)}$ vs. V_{GS}

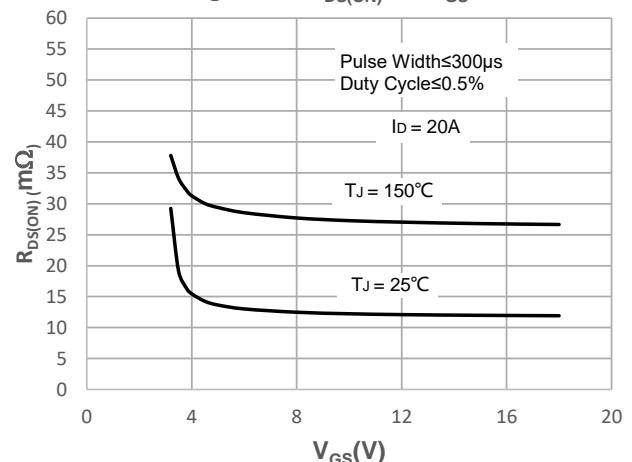
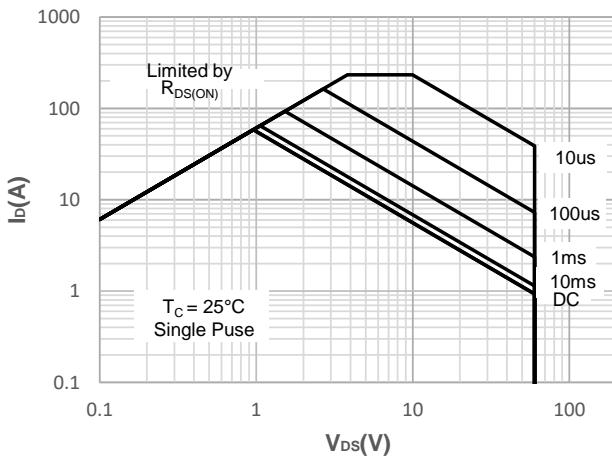


Figure 15: Maximum Safe Operating Area



Test Circuit

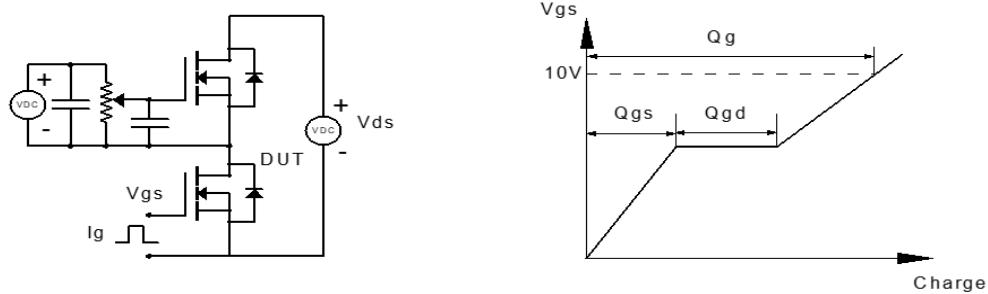


Figure 1: Gate Charge Test Circuit & Waveform

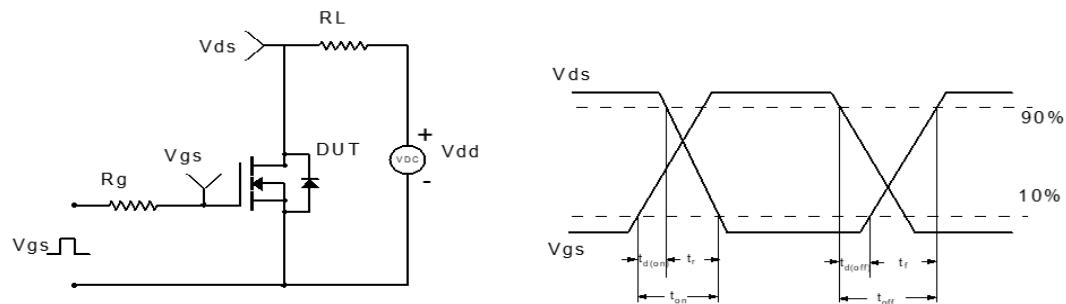


Figure 2: Resistive Switching Test Circuit & Waveform

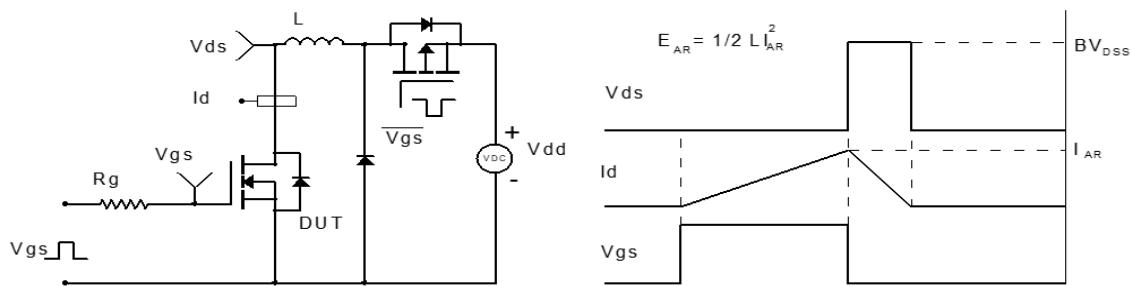


Figure 3: Unclamped Inductive Switching Test Circuit & Waveform

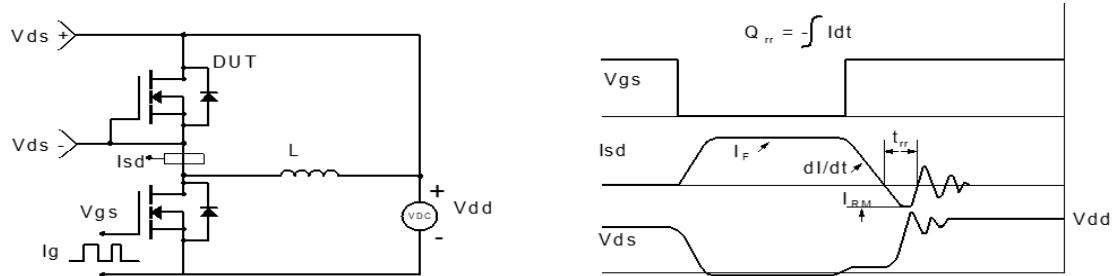
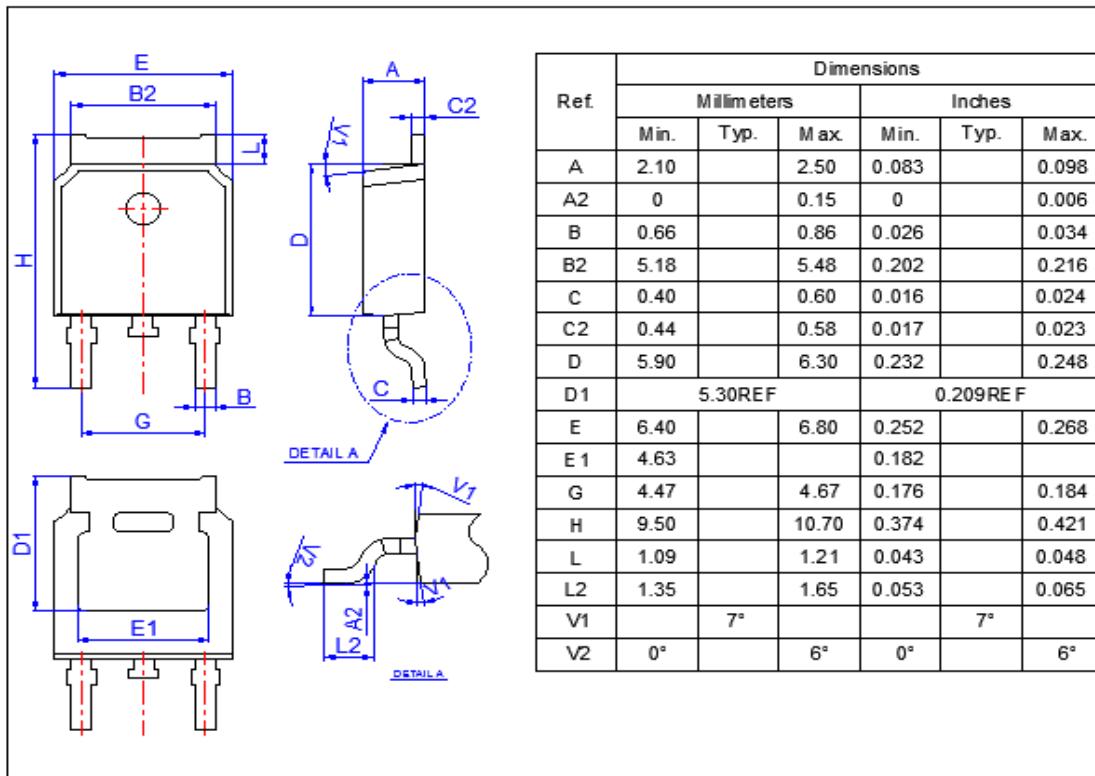
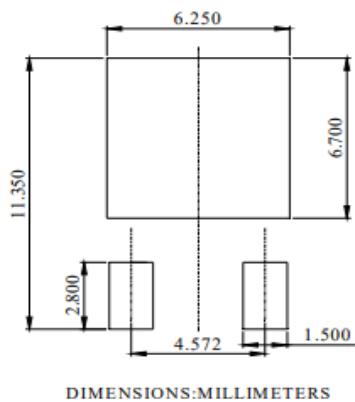


Figure 4: Diode Recovery Test Circuit & Waveform

Package Mechanical Data(TO-252-3L)



Recommended Soldering Footprint



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